Electronic Supplementary Information

**Fig. S1** TEM image of SnO\textsubscript{2} NPs (aggregated during TEM sample preparation). Scale bar: 50 nm

**Fig. S2** XRD patterns of SnO\textsubscript{2} NPs and resultant SnO\textsubscript{2} microcapsules. Suspensions were dried prior to XRD measurement. Data were obtained with a powder diffractometer (Rigaku D/Max-2100PC) using unfiltered Cu-K\textalpha radiation (\lambda = 1.5406 Å) at 40 kV and 40 mA.